

<b>Notice of References Cited</b>	Application/Control No. 10/595,434		Applicant(s)/Patent Under Reexamination KARG ET AL.	
	Examiner JOEL G. HORNING		Art Unit 1792	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0063212	05-2002	Mirkin et al.	250/306
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
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	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Asahino et al (Physical Review Letters, Volume 86(2001), Number 19, pp 4334-4337).
	V	Takahashi et al (Ultramicroscopy, Volume 82 (2000), pp63-68).
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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